

Application/Control No.	Applicant(s)/Patent under Reexamination VAN NIEUWSTADT, MICHIEL JACQUES							
09/682,443								
Examiner	Art Unit							
Tu M. Nguyen	3748							

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	RIGINAL		CROSS REFERENCE(S) SUBCLASS (ONE SUBCLASS PER BLOCK)											
CLASS	SUBCLASS	CLASS												
60	286	60	274	276	277	284	303							
INTERNATION	IAL CLASSIFICATION													
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Tu M. Nguyen

	Claims renumbered in the same order as presented by applicant								o C	PA		☐ T.D.			☐ R.1.47				
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1]		31			61			91			121			151			181
	2			32			62			92			122			152			182
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	4			34			64			94			124			154			184
	5			35			65			95			125			155			185
	6			36			66			96			126			156			186
	1			37			67			97			127			157			187
	8			38			68			98			128			158			188
	9			39			69			99			129	1		159			189
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	11			41			71			101			131			161			191
	12]		42			72			102			132			162			192
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	14			44			74			104			134			164			194
	15			45			75			105			135			165			195
	16]		46			76			106			136			166			196
	17			47			77			107			137			167			197
	18]		48			78			108			138			168			198
	19]		49			79			109			139			169			199
	20]		50			80		- :	110			140			170			200
5	(21)]		51			81			111			141			171		-	201
6	22			52			82			112			142			172			202
7	23] :		53			83			113			143			173			203
8	24			54			84			114			144			174			204
	24 (25)]		55			85			115			145			175			205
2	26			56			86			116			146			176			206
3	27]		57	į		87			117			147			177			207
4	28			58			88			118			148			178			208
	29			59			89			119			149			179			209
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